

Claims

- Sub A1
- [c1] 1. A signal inspection device for testing a plurality of electronic devices that receive inputs and output outputs signals in response thereto, said signal inspection device comprising a memory circuit for storing an inspection program adapted to electronic devices to be inspected, said memory circuit being capable of being programmed by an external personal computer, a power supply for applying input signals to an electronic device from said signal inspection device, and a display for receiving and displaying output signals from the electronic device being tested in response to the applied input signals.
- [c2] 2. A signal inspection device as set forth in claim 1, wherein the display operates independently of any personal computer.
- [c3] 3. A signal inspection device as set forth in claim 1, wherein the memory circuit comprises an EEPROM.
- [c4] 4. A signal inspection device as set forth in claim 3, characterized in that the inspection program is created as an interactive type of displayed image on the personal computer and transferred therefrom to the memory circuit.
- [c5] 5. A method for testing a plurality of electronic devices that receive inputs and outputs output signals in response thereto comprising the steps of applying an input signal to the tested electronic device from a power supply of a signal inspection device comprising a memory circuit for storing an inspection program adapted to the electronic device and capable of being programmed by an external personal computer, and displaying the output signal from the electronic device being tested in response to the applied input signals on a display of the signal inspection device.